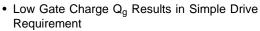


N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMM	ARY	
V _{DS} (V)	650)
R _{DS(on)} (Ω)	V _{GS} = 10 V	1.7
Q _g (Max.) (nC)	11	
Q _{gs} (nC)	2.3	3
Q _{gd} (nC)	5.2	2
Configuration	Sing	le

FEATURES



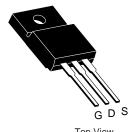


• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

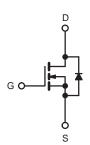


- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





Top View



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS To	_C = 25 °C, unl	ess otherw	ise noted		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	650	V
Gate-Source Voltage			V_{GS}	± 30	7
Continuous Drain Currente	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	1	2.0	
Continuous Drain Current	VGS at 10 V	T _C = 100 °C	I _D	1.28	Α
Pulsed Drain Current ^a			I _{DM}	8	
Linear Derating Factor				0.48	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	165	mJ
Repetitive Avalanche Current ^a			I _{AR}	2	Α
Repetitive Avalanche Energy ^a			E _{AR}	6	mJ
Maximum Power Dissipation	T _C = 2	5 °C	P_{D}	25	W
Peak Diode Recovery dV/dtc			dV/dt	2.8	V/ns
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature) ^d	for 10) s		300	
Mounting Torque	uting Torque 6-32 or M3 screy			10	lbf ⋅ in
Mounting Forque	0-32 01 1013	SCIEM		1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T $_J$ = 25 °C, L = 24 mH, R $_G$ = 25 Ω , I $_{AS}$ = 3.2 A (see fig. 12). c. I $_{SD}$ ≤ 3.2 A, dI/dt ≤ 90 A/ μ s, V $_{DD}$ ≤ V $_{DS}$, T $_J$ ≤ 150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RAT	TINGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.1	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA ^d	-	670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 30 V	ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 650 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1 A b	-	4.0	5.0	Ω
Forward Transconductance	9 _{fs}	+	= 50 V, I _D = 1 A	3.9	-	-	S
Dynamic					l		
Input Capacitance	C _{iss}	V 0V		-	1000	-	_
Output Capacitance	C _{oss}		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		45	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	ı	5	-	pF
Outrat Outration	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	912	-	
Output Capacitance		$V_{GS} = 0 V$	V _{DS} = 520 V, f = 1.0 MHz	-	26		
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 520 V ^c	-	42	-	
Total Gate Charge	Qg			-	-	11	
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V	$I_D = 1.2 \text{ A}, V_{DS} = 400 \text{ V}$ see fig. 6 and 13^b	-	-	2.3	nC
Gate-Drain Charge	Q_{gd}			-	-	5.2	
Turn-On Delay Time	t _{d(on)}	1		-	14	-	†
Rise Time	t _r		= 325 V, I _D = 1.2A	i	20	-	1
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$	$R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. 10^b		34	-	ns -
Fall Time	t _f	1		-	18	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	/ I: T/		-	2	A
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode		ı	-	8	Α
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 3.2 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 3.2 A, dl/dt = 100 A/μs ^b		-	180	230	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					L _D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %. c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

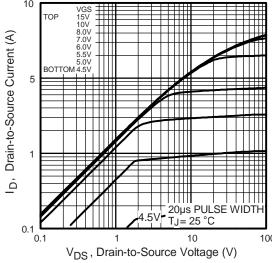
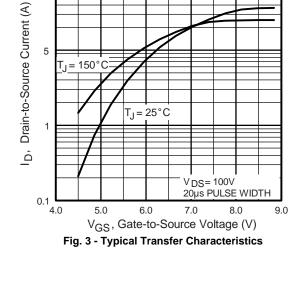


Fig. 1 - Typical Output Characteristics



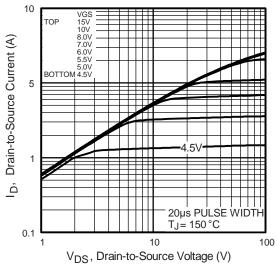


Fig. 2 - Typical Output Characteristics

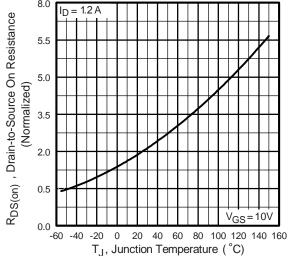


Fig. 4 - Normalized On-Resistance vs. Temperature



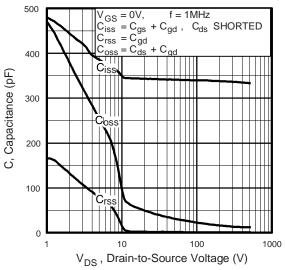


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

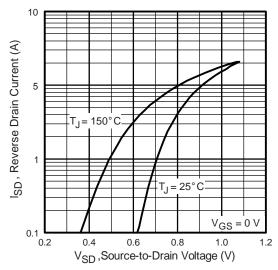


Fig. 7 - Typical Source-Drain Diode Forward Voltage

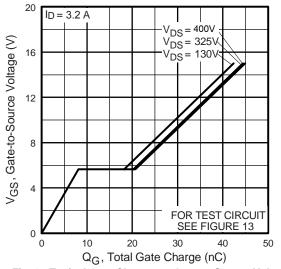


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

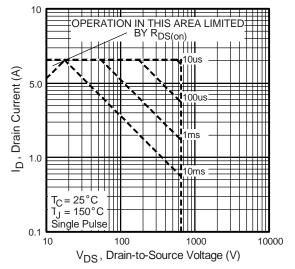


Fig. 8 - Maximum Safe Operating Area



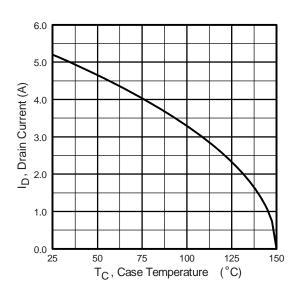


Fig. 9 - Maximum Drain Current vs. Case Temperature

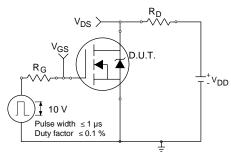


Fig. 10a - Switching Time Test Circuit

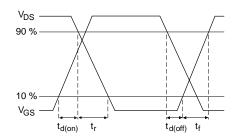


Fig. 10b - Switching Time Waveforms

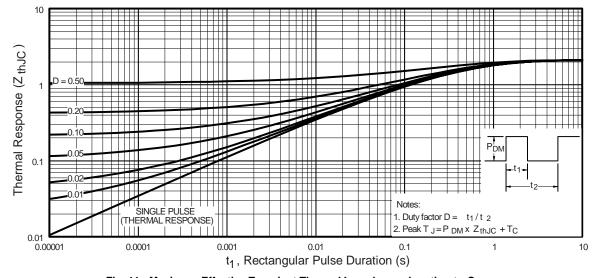


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

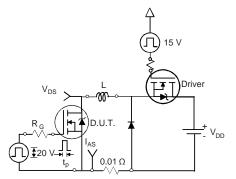


Fig. 12a - Unclamped Inductive Test Circuit

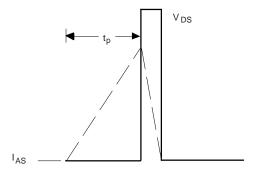


Fig. 12b - Unclamped Inductive Waveforms



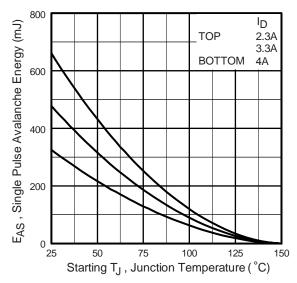


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

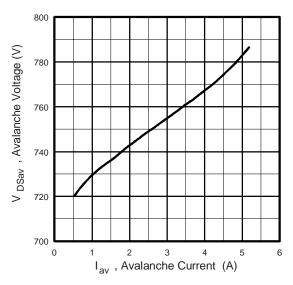


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

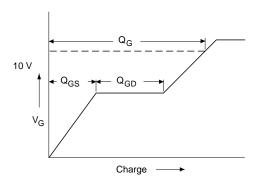


Fig. 13a - Basic Gate Charge Waveform

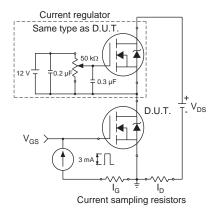
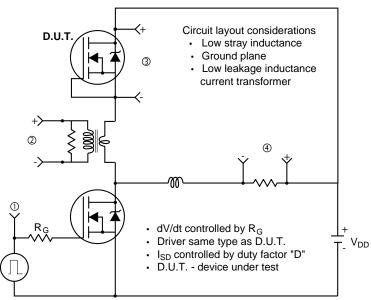
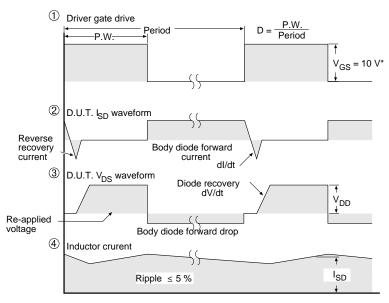


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



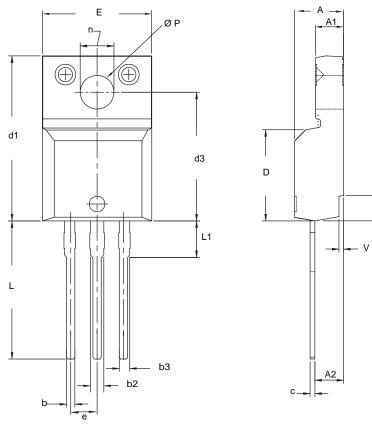


* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
Е	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
٧	0.400	0.500	0.016	0.020

DWG: 5972

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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